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PATENT NUMBER and ISSUE DATE

U.S. UTILITY Patent Application

: APPL NUM 10035247	FILING DATE 01/04/2002	CLASS 257	SUBCLASS 750	GAU 2814 2814	EXAMINER WILSON			
"APPLICANTS: Yi Sang Hyun; Kim Young Nam;								
**CONTINUING DATA VERIFIED:								
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** FOREIGN APPLICATIONS VERIFIED:								
REPUBLIC OF	KOREA 2001-848	0 02/20/2	2001					
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35 USC 119 cenditi Verified and Acknow	ions met wledged Examiners's in		s ⊒ no		262/009			
TITLE: Semiconductor device having no cracks in one or more layers underlying a metal line layer and method of manufacturing the same								
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NOTICE OF ALLOWANCE MAILED			CLAIMS ALLOWED					
		Assistant Examiner	Total Claims		Print Claim for O.G			
ISSUE FEE			DRAWING					
Amount Due	Date Paid	7	Sheets Drwg.	Figs.Drwg	Print Fig.			
	<u> </u>	Primary Examiner	iner					
TERMINAL		PREPARED FOR ISSUE	Applicati n Examiner					
]	DISCLAMER	WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368, Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.						
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